



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Shunpei Yamazaki et al. Art Unit : 2825
Serial No. : 09/995,549 Examiner : Granvill D. Lee
Filed : November 27, 2001
Title : SEMICONDUCTOR THIN FILM, SEMICONDUCTOR DEVICE AND
MANUFACTURING METHOD THEREOF

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

The U.S. patents listed on the attached form PTO-1449 are submitted. In accordance with the PTO's waiver of 37 CFR 1.98 (a)(2)(iii), copies of the patents are not enclosed.

This statement is being filed after a first Office action on the merits, but before receipt of a final Office action or a Notice of Allowance. A check for \$180 in payment of the late submission fee of C.F.R. § 1.17(p) is enclosed. Please apply any other charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date: 12/10/04



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Sheet 1 of 1

Substitute Form PTO-1449 (Modified) Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 07977-124003	Application No. 09/995,549
	Applicant Shunpei Yamazaki et al.		
	Filing Date November 27, 2001	Group Art Unit 2825	

U.S. Patent Documents

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	5,576,556	11/19/1996	Takemura et al.			08/16/1994
	AB	5,648,277	07/15/1997	Zhang et al.			11/02/1994
	AC	5,923,968	07/13/1999	Yamazaki et al.			09/08/1995
	AD	5,962,897	10/05/1999	Takemura et al.			06/30/1997
	AE	6,218,678 B1	04/17/2001	Zhang et al.			03/11/1997
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						

Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AM							
	AN							
	AO							
	AP							
	AQ							

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
	AR	
	AS	
	AT	
	AU	

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	